

**Notice of References Cited**

Application/Control No.

10/537,277

Applicant(s)/Patent Under

Reexamination

ONODA, YOSHIO

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NED A. WALKER

Art Unit

3781

Page 1 of 4

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ONODA, YOSHIO

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NED A. WALKER

Art Unit

3781

Page 2 of 4

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ONODA, YOSHIO

Examiner

NED A. WALKER

Art Unit

3781

Page 3 of 4

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NED A. WALKER

Art Unit

3781

Page 4 of 4

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